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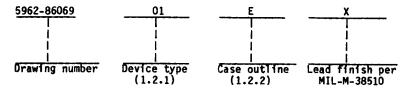
<u>DISTRIBUTION STATEMENT A.</u> Approved for public release; distribution is unlimited.

DESC FORM 193



1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type

Generic number

Circuit function

01

54F85

4-bit magnitude comparator

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter

E F 2 Case outline

D-2 (16-lead, 1/4" x 7/8"), dual-in-line package F-5 (16-lead, 1/4" x 3/8"), flat package C-2 (20-terminal, .350" x .350"), square chip carrier package

1.3 Absolute maximum ratings.

1.4 Recommended operating conditions.

1/ Must withstand the added PD due to short circuit test (e.g., IOS).
2/ When a thermal resistance for this case is specified in MIL-M-38510, appendix C, that value shall supersede the value specified herein.

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2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

- Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.
 - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

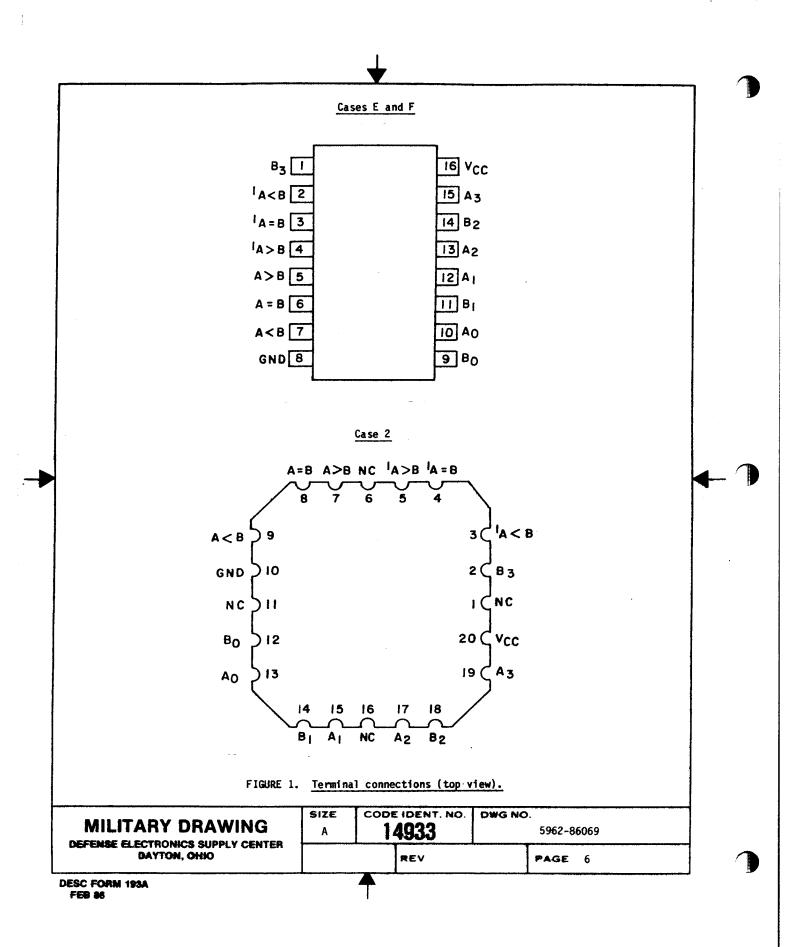
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7	ļ	Į.			I	-	Limits	T
Test	Symbol	 -5: unles:	5°C < T	tions C < +125°C wise specifie	lGroup Isubgro	A oupsi Mi	n Max	Unit
High level output voltage	УОН	VCC = 4.5		H = -1 mA 2.0 V	1,2	,3 2.	5 	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
Low level output voltage	IV _{OL}				1,2,	,3	0.5) V
Input clamp voltage		V _{CC} = 4.5 I _{IN} = -18		c = +25°C	1	 	-1.2	 Y
High level input current	IIH1	 V _{CC} = 5.5	v; v _I	N = 7.0 V	1,2,	3	100	ĮμA
	I _{IH2}	V _{CC} = 5.5	V; V _I	y = 2.7 V	1,2,	3	20	μA
Low level input current	IIIL	 V _{CC} = 5.5 	v; v _{II}	y = 0.5 Y	1,2,	3	-20	i μA
Short circuit output current	IIos	 V _{CC} = 5.5	V; V _O (JT = GND <u>1</u> /	1,2,	3 -60	-150	mA
Supply current	ICCH	V _{CC} = 5.5	٧		1,2,	3	50	mA
	ICCL				1,2,	3	54	mA
Functional tests		See 4.4.1	С	**	1 7			
Propagation delay time, A or B to A < B or A > B	tpLH1	 V _{CC} = 5.0 R _L = 500Ω	٧ ±5%		9		1 16 21	ns ns
	tPHL1	C_ = 50 p	F ±10%		10,1		1 16	ns ns
Propagation delay time, A or B to A = B	l tpLH2				9		1 16	ns ns
	tpHL2				10,1		14	ns ns
Propagation delay time, A < B or 1A = B to A > B	t _{PLH3}				9		9	ns
	tpHL3				10,11		1 8 1	ns ns
ropagation delay time, A = B to A = B					9		8 8 14	ns
	tpHL4				10,11		10	ns ns
ropagation delay time, A > B or 1A = B to A < B	 tpLH5				9 10,11		9 1	ns ns
	tpHL5				1 9		1 9 1	ns ns
Not more than one output sh condition should not exceed	ould be si one seco	norted at	a time	, and the dur	ation of the	short o	ircuit	113
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- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, B, C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 7 tests shall verify the truth table.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - (1) Test condition A, B, C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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8 11 4 Outputs | 8 しェーエーエーエーエー ≤. 8 ^ 8 ×××××× н _< Cascading inputs 8 ××××××× _< Truth table. æ $\times = \bot$ LLIXXXXXX ^ ⋖ FIGURE 2. ××××××000000 **ಲ್ಲಿ** စ္မ 11 11 11 څ 22222 222 81 81 81 B₁ ^ V II II II II II H II H Comparing inputs 82 82 82 = HIGH voltage level = LOW voltage level = Don't care 81 ^ V H H H H H H H D 11 11 933 933 m**B**3 H II H 11 11 11 DWG NO. CODE IDENT. NO. SIZE 14933 5962-86069 MILITARY DRAWING Α **DEFENSE ELECTRONICS SUPPLY CENTER** PAGE 7 REV DAYTON, OHIO **DESC FORM 193A**

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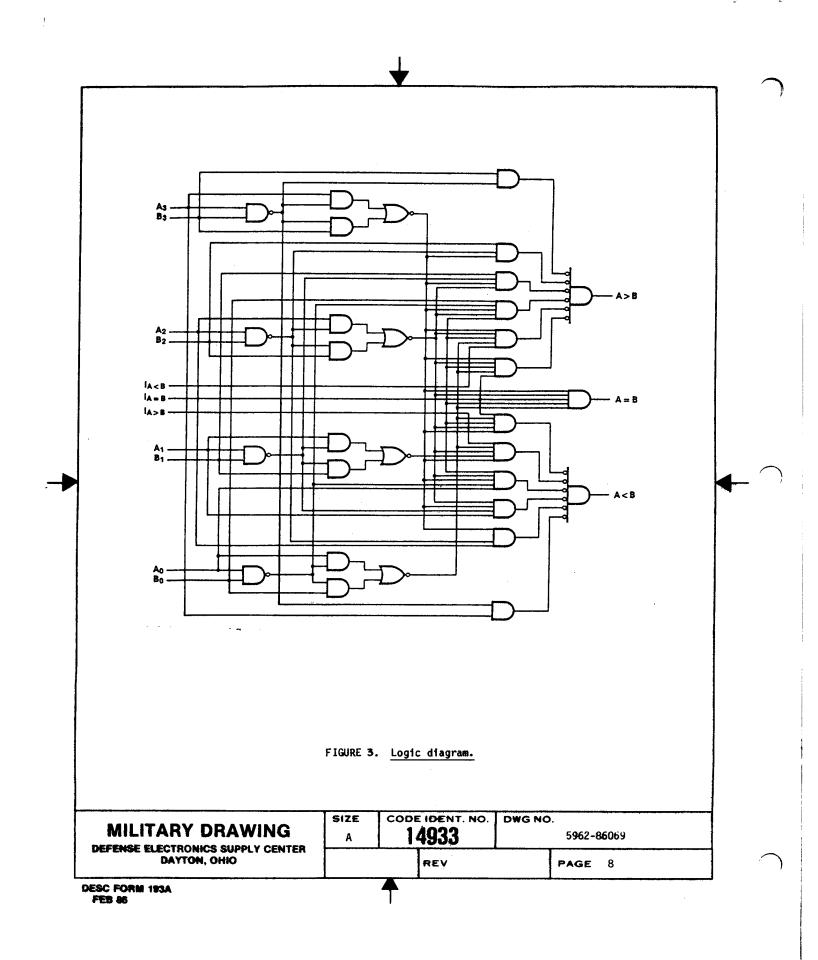


TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004) 	
Final electrical test parameters	
(method 5004)	
Group A test requirements	11, 2, 3, 7, 9
(method 5005)	10, 11**
Groups C and D end-point	1, 2, 3
electrical parameters	
(method 5005)	

*PDA applies to subgroup 1.

5. PACKAGING

- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- 6. NOTES
- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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^{**}Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Yendor CAGE number	Vendor similar part number 1/
5962-8606901EX	18324	54F85/BEA
5962-8606901FX	18324	54F85/BFA
5962-86069012X	18324	54F85/B2C

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

18324

Vendor name and address

Signetics Corporation 4130 S. Market Court Sacramento, CA

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